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- High-Current 3-State Noninverting Outputs Drive Bus Lines Directly or up to 15 LSTTL Loads
- Bus-Structured Pinout
- Package Options Include Plastic Small-Outline (DW), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

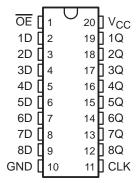
### description

These octal edge-triggered D-type flip-flops feature 3-state outputs designed specifically for bus driving. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

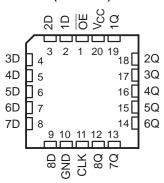
The eight flip-flops enter data on the low-to-high transition of the clock (CLK) input.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

SN54HC574 . . . J OR W PACKAGE SN74HC574 . . . DW, N, OR PW PACKAGE (TOP VIEW)



SN54HC574 . . . FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54HC574 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC574 is characterized for operation from –40°C to 85°C.

### FUNCTION TABLE (each flip-flop)

	INPUTS	OUTPUT	
OE	CLK	D	Q
L	<b>↑</b>	Н	Н
L	$\uparrow$	L	L
L	H or L	Χ	Q <sub>0</sub>
Н	Χ	Χ	Z

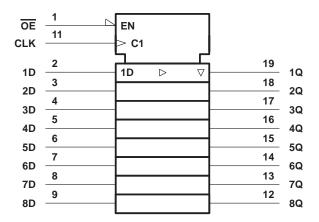


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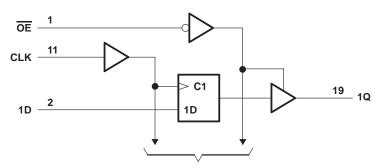
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### logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### logic diagram (positive logic)



To Seven Other Channels

### absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V <sub>CC</sub>	–0.5 V to 7 V
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CC}$ ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	
Continuous current through V <sub>CC</sub> or GND	±70 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): DW package	
N package	67°C/W
PW package	128°C/W
Storage temperature range, T <sub>stg</sub>	65°C to 150°C

<sup>&</sup>lt;sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.



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### recommended operating conditions (see Note 3)

			SI	SN54HC574		SN	174HC57	'4	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
VCC	Supply voltage		2	5	6	2	5	6	V
		V <sub>CC</sub> = 2 V	1.5			1.5			
VIΗ	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V
		V <sub>CC</sub> = 6 V	4.2			4.2			
		V <sub>CC</sub> = 2 V	0		0.5	0		0.5	
VIL	Low-level input voltage	V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	V
		V <sub>CC</sub> = 6 V	0		1.8	0		1.8	
٧ı	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
		V <sub>CC</sub> = 2 V	0		1000	0		1000	
t <sub>t</sub>	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		V <sub>CC</sub> = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	MULTIONS	VCC	Т	A = 25°C	;	SN54H	IC574	SN74H	C574	UNIT						
PARAMETER	1231 00	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII						
			2 V	1.9	1.998		1.9		1.9								
		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4								
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V						
		I <sub>OH</sub> = -6 mA	4.5 V	3.98	4.3		3.7		3.84								
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34								
	VI = VIH or VIL		2 V		0.002	0.1		0.1		0.1							
		I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1		0.1		0.1							
VOL			6 V		0.001	0.1		0.1		0.1	V						
									I <sub>OL</sub> = 6 mA	4.5 V		0.17	0.26		0.4		0.33
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33							
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA						
loz	$V_O = V_{CC}$ or 0		6 V		±0.01	±0.5		±10		±5	μΑ						
Icc	$V_I = V_{CC}$ or 0,	IO = 0	6 V			8		160		80	μΑ						
C <sub>i</sub>		·	2 V to 6 V		3	10		10		10	pF						

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# timing requirements over recommended operating free-air temperature range (unless otherwise noted)

		Vaa	T <sub>A</sub> =	25°C	SN54F	IC574	SN74H	C574	UNIT
		VCC	MIN	MAX	MIN	MAX	MIN	MAX	UNII
		2 V		6		4		5	
fclock	Clock frequency	4.5 V		30		20		24	MHz
		6 V		38		24		28	
	Pulse duration, CLK high or low	2 V	80		120		100		
t <sub>W</sub>		4.5 V	16		24		20		ns
		6 V	14		20		17		
		2 V	100		150		125		
t <sub>su</sub>	Setup time, data before CLK↑	4.5 V	20		30		25		ns
		6 V	17		26		21		
	Hold time, data after CLK↑	2 V	5		5		5		ns
th		4.5 V	5		5		5		
		6 V	5		5		5		

# switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	T <sub>A</sub> = 25°C		SN54H	IC574	SN74H	IC574	UNIT				
PARAMETER	(INPUT)	(OUTPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT			
			2 V	6	11		4		5						
fmax			4.5 V	30	36		20		24		MHz				
			6 V	36	40		24		28						
			2 V		90	180		270		225					
<sup>t</sup> pd	CLK	Any Q	4.5 V		28	36		54		45	ns				
			6 V		24	31		46		38					
			2 V		77	150		225		190					
t <sub>en</sub>	OE	OE	Any Q	Any Q	Any Q	Any Q	4.5 V		26	30		45		38	ns
			6 V		23	26		38		32					
			2 V		52	150		225		190					
<sup>t</sup> dis	ŌĒ	Any Q	4.5 V		24	30		45		38	ns				
			6 V		22	26		38		32					
			2 V		28	60		90		75					
t <sub>t</sub>		Any Q	4.5 V		8	12		18		15	ns				
			6 V		6	10		15		13					

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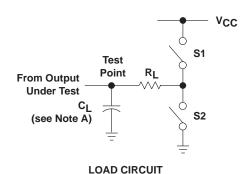
## switching characteristics over recommended operating free-air temperature range, $C_L$ = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	\ = 25°C	;	SN54H	IC574	SN74H	C574	UNIT
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	6					5		
f <sub>max</sub>			4.5 V	30					24		MHz
			6 V	36					28		
			2 V		105	265		400		330	
t <sub>pd</sub>	CLK	CLK Any Q	4.5 V		36	53		80		66	ns
			6 V		31	46		68		57	
	ŌĒ	Any Q	2 V		95	235		355		295	
t <sub>en</sub>			Any Q	4.5 V		32	47		71		59
			6 V		28	41		60		51	
		Any Q	2 V		60	210		315		265	
t <sub>t</sub>			4.5 V		17	42		63		53	ns
			6 V		14	36		53		45	

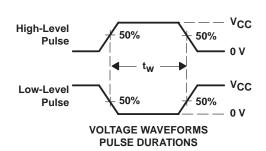
### operating characteristics, $T_A = 25^{\circ}C$

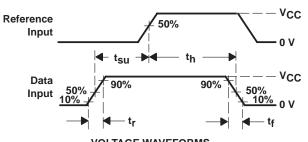
		PARAMETER	TEST CONDITIONS	TYP	UNIT
Γ	C <sub>pd</sub> Po	ower dissipation capacitance per flip-flop	No load	100	pF

#### PARAMETER MEASUREMENT INFORMATION

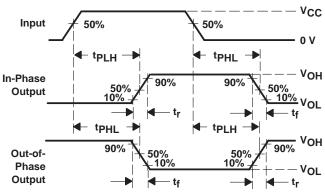


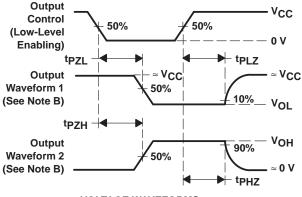
PARAI	METER	RL	CL	S1	S2
	tPZH	1 <b>k</b> Ω	50 pF or	Open	Closed
ten	tPZL	1 1		Closed	Open
<b>.</b>	tPHZ	1 kΩ	50 pF	Open	Closed
<sup>t</sup> dis	tPLZ	1 K22	30 pr	Closed	Open
t <sub>pd</sub> or t <sub>t</sub>		_	50 pF or 150 pF	Open	Open





**VOLTAGE WAVEFORMS** SETUP AND HOLD AND INPUT RISE AND FALL TIMES





**VOLTAGE WAVEFORMS** PROPAGATION DELAY AND OUTPUT TRANSITION TIMES

**VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS** 

NOTES: A. C<sub>L</sub> includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_r = 6$  ns,  $t_f = 6$  ns.
- D. For clock inputs, f<sub>max</sub> is measured when the input duty cycle is 50%.
- E. The outputs are measured one at a time with one input transition per measurement.
- F. tpLz and tpHz are the same as t<sub>dis</sub>.
- G. tpzL and tpzH are the same as ten.
- H. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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